

Search Notes

Application/Control No.

10/762,210

Examiner

Taeyoon Kim

Applicant(s)/Patent under
Reexamination

BERENSON ET AL.

Art Unit

1651

SEARCHED

Class	Subclass	Date	Examiner
435	375	6/2/2008	TK
435	325	6/2/2008	YK
435	372.3	6/2/2008	TK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
435	375	6/2/2008	TK
435	325	6/2/2008	TK
435	372.3	6/2/2008	TK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search: classification, interference search	6/2/2008	TK